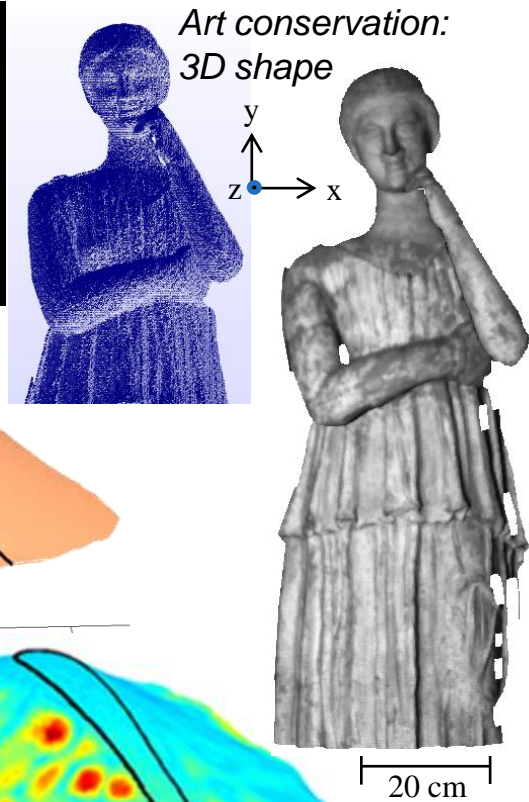
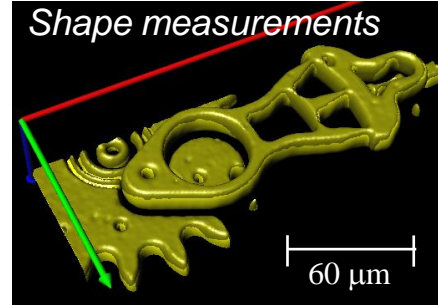
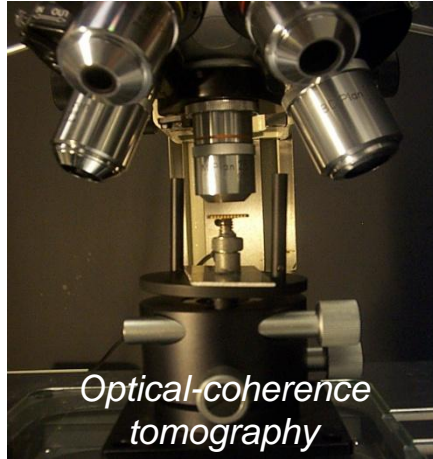
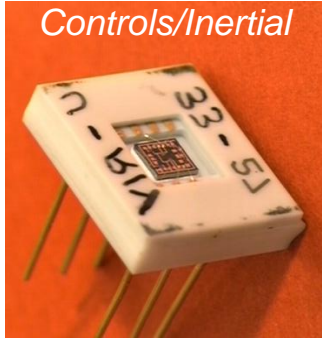


Miniaturization engineering: development and application of advanced optical metrology systems

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MEMS/MOEMS are enabling the development of advanced optical metrology systems for challenging applications and for testing components under actual operating conditions.



Digital holographic system deployed at a clinic

